

Inventor: Craig M. Carpenter; Ross S. Dando; Philip H. Campbell;  
Allen P. Mardian; Jeff N. Fuss; Randy W. Mercil

Title: Chemical Vapor Deposition Apparatuses and Deposition  
Methods

Assignee: Micron Technology, Inc.

Attorney Docket No. MI22-1559

### INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449

### REMARKS


The citations listed, copies attached, may be material to the examination of the subject application and are therefore submitted in compliance with the duty of disclosure defined in 37 CFR §1.56. The Examiner is requested to make these citations of official record in this application. No admission is made regarding whether all the submitted references are prior art.

The materials cited are presented to assist in and expedite examination of this application. The present invention is considered to be patentable over the cited materials. Expeditious examination and allowance of this application as a patent are therefore urged in order that the public may benefit from the disclosure and commercialization of the invention.

EL465855526

Respectfully submitted,

Dated: 8 March 2001

Inventor:   
Craig M. Carpenter

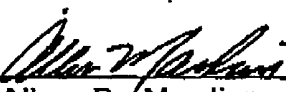
Dated: 3/8/01

Inventor:   
Ross S. Dando

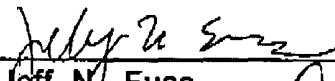
Dated: March 8, 01

Inventor:   
Philip H. Campbell

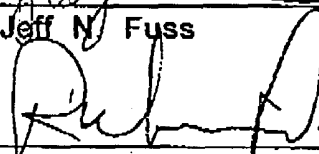
Dated: 3-8-01

Inventor:   
Allen P. Mardian

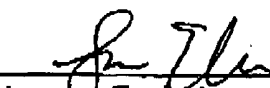
Dated: 3-8-01

Inventor:   
Jeff N. Fuss

Dated: 03/08/01

Inventor:   
Randy W. Mercil

Dated: 15 Mar 2001

Attorney:   
James E. Lake  
Reg. No.: 44,854

**COPY**

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOLL. NO. M122-1559		SERIAL NO. Filed Herewith		
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Craig M. Carpenter et al		COPY		
				FILING DATE Filed Herewith				GROUP Unknown
U.S. PATENT DOCUMENTS								
*Examiner (Initial)		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	5,885,358	3/23/99	Maydan et al				
	AB							
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